

Mail Date
11-21-01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

TEUNIS WILLEM TUKKER

NL 000628

Serial No.

Group Art Unit

Filed: CONCURRENTLY

Ex.

Title: MEASUREMENT OF SURFACE DEFECTS

Commissioner for Patents
Washington, D.C. 20231

#5/A
4-6-02
Q.C.

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination, please amend the above-identified application as follows:

IN THE CLAIMS

Please amend the claims as follows:

4. (amended) A device as claimed in claim 1, characterized in that the superposition of the reference beam (6) and the reflected light (15) is formed in the optical beam path and that the superposition image thus obtained can be projected into an entrance window of a detector (16).

5. (amended) A device as claimed in claim 1, characterized in that the input signal formed by the superposition of the reference